

**Search Notes**

Application/Control No.

10/623,760

Examiner

Tim Phan

Applicant(s)/Patent under  
Reexamination

MIYA ET AL.

Art Unit

3729

29/598

**SEARCHED**

Class	Subclass	Date	Examiner
29	598	2/7/2006	TP
	566.1		
	596, 597		
	732, 735		
	736		
242	432.6		
310	71, 90		
	216		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST Search Attached	2/7/2006	TP